

E 197955267

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. .... 09/388,857  
Filing Date ..... September 1, 1999  
Inventor ..... Luan C. Tran  
Assignee ..... Micron Technology, Inc.  
Group Art Unit ..... 2813  
Examiner ..... L. Schillinger  
Attorney's Docket No. .... MI22-878  
Title: Semiconductor Processing Methods Of Forming Transistors, Semiconductor  
Processing Methods Of Forming Dynamic Random Access Memory Circuitry, And  
Related Integrated Circuitry

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

References - - See attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the references listed on the attached Form PTO-1449. No admission is made regarding whether the submitted references are prior art.

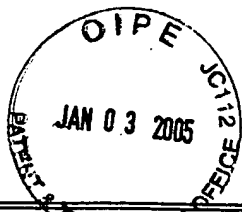
Citation of these references is respectfully requested.

Respectfully submitted,

Date: 3-18-04

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Sheet 1 of 1

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-378SERIAL NO.  
09-388,337LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)APPLICANT  
Luan C. TranFILING DATE  
September 1, 1999GROUP  
2813

## U.S. PATENT DOCUMENTS

| *Examiner Initial |    | Document Number | Date      | Name              | Class | Subclass | Filing Date If Appropriate |
|-------------------|----|-----------------|-----------|-------------------|-------|----------|----------------------------|
|                   | AA | 6,545,904 B2    | 04/08/03  | Tran              |       |          |                            |
|                   | AB | 6,492,693 B2    | 12/10/02  | Tran              |       |          |                            |
|                   | AC | 6,649,461 B1    | 11/18/03  | Lai et al.        |       |          |                            |
|                   | AD | 2002/0020106 A1 | 01/30/03  | Tran              |       |          |                            |
|                   | AE | 6,281,082 B1    | 08/28/01  | Chen et al.       |       |          |                            |
|                   | AF | 5,691,215       | 11/25/97  | Dai et al.        |       |          |                            |
|                   | AG | 6,261,914 B1    | 07/17/01  | Divakaruni et al. |       |          |                            |
|                   | AH | 6,426,534 B1    | 078/30/02 | Look et al.       |       |          |                            |
|                   | AI |                 |           |                   |       |          |                            |
|                   | AJ |                 |           |                   |       |          |                            |
|                   | AK |                 |           |                   |       |          |                            |

## FOREIGN PATENT DOCUMENTS

|  |    | Document Number | Date | Country | Class | Subclass | Translation |    |
|--|----|-----------------|------|---------|-------|----------|-------------|----|
|  |    |                 |      |         |       |          | Yes         | No |
|  | AL |                 |      |         |       |          |             |    |
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|  | AN |                 |      |         |       |          |             |    |
|  | AO |                 |      |         |       |          |             |    |
|  | AP |                 |      |         |       |          |             |    |

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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|  | AQ |  |  |
|  | AR |  |  |

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, \*whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.